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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	16825
Number of Logic Elements/Cells	215360
Total RAM Bits	13455360
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	676-BBGA, FCBGA
Supplier Device Package	676-FCBGA (27x27)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc7a200t-2fbg676i">https://www.e-xfl.com/product-detail/xilinx/xc7a200t-2fbg676i</a>

Table 1: Absolute Maximum Ratings<sup>(1)</sup> (Cont'd)

Symbol	Description	Min	Max	Units
<b>Temperature</b>				
T <sub>STG</sub>	Storage temperature (ambient)	-65	150	°C
T <sub>SOL</sub>	Maximum soldering temperature for Pb/Sn component bodies <sup>(6)</sup>	-	+220	°C
	Maximum soldering temperature for Pb-free component bodies <sup>(6)</sup>	-	+260	°C
T <sub>j</sub>	Maximum junction temperature <sup>(6)</sup>	-	+125	°C

**Notes:**

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).
- The maximum limit applied to DC signals.
- For maximum undershoot and overshoot AC specifications, see [Table 4](#).
- For soldering guidelines and thermal considerations, see [UG475: 7 Series FPGA Packaging and Pinout Specification](#).

Table 2: Recommended Operating Conditions<sup>(1)(2)</sup>

Symbol	Description	Min	Typ	Max	Units
<b>FPGA Logic</b>					
V <sub>CCINT</sub>	Internal supply voltage	0.95	1.00	1.05	V
	For -2L (0.9V) devices: internal supply voltage	0.87	0.90	0.93	V
V <sub>CCAUX</sub>	Auxiliary supply voltage	1.71	1.80	1.89	V
V <sub>CCBRAM</sub>	Block RAM supply voltage	0.95	1.00	1.05	V
V <sub>CCO</sub> <sup>(3)(4)</sup>	Supply voltage for 3.3V HR I/O banks	1.14	-	3.465	V
V <sub>IN</sub> <sup>(5)</sup>	I/O input voltage	-0.20	-	V <sub>CCO</sub> + 0.20	V
	I/O input voltage for V <sub>REF</sub> and differential I/O standards	-0.20	-	2.625	V
I <sub>IN</sub> <sup>(6)</sup>	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	-	-	10	mA
V <sub>CCBATT</sub> <sup>(7)</sup>	Battery voltage	1.0	-	1.89	V
<b>GTP Transceiver</b>					
V <sub>MGTAVCC</sub> <sup>(8)(9)</sup>	Analog supply voltage for the GTP transmitter and receiver circuits	0.97	1.0	1.03	V
V <sub>MGTAVTT</sub> <sup>(8)(9)</sup>	Analog supply voltage for the GTP transmitter and receiver termination circuits	1.17	1.2	1.23	V
<b>XADC</b>					
V <sub>CCADC</sub>	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V <sub>REFP</sub>	Externally supplied reference voltage	1.20	1.25	1.30	V

**Table 3: DC Characteristics Over Recommended Operating Conditions (Cont'd)**

Symbol	Description	Min	Typ <sup>(1)</sup>	Max	Units
n	Temperature diode ideality factor	—	1.010	—	—
r	Temperature diode series resistance	—	2	—	Ω

**Notes:**

1. Typical values are specified at nominal voltage, 25°C.
2. This measurement represents the die capacitance at the pad, not including the package.
3. Maximum value specified for worst case process at 25°C.
4. Termination resistance to a V<sub>CCO</sub>/2 level.

**Table 4: V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot for 3.3V HR I/O Banks<sup>(1)</sup>**

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
V <sub>CCO</sub> + 0.40	100	-0.40	100
V <sub>CCO</sub> + 0.45	100	-0.45	61.7
V <sub>CCO</sub> + 0.50	100	-0.50	25.8
V <sub>CCO</sub> + 0.55	100	-0.55	11.0
V <sub>CCO</sub> + 0.60	46.6	-0.60	4.77
V <sub>CCO</sub> + 0.65	21.2	-0.65	2.10
V <sub>CCO</sub> + 0.70	9.75	-0.70	0.94
V <sub>CCO</sub> + 0.75	4.55	-0.75	0.43
V <sub>CCO</sub> + 0.80	2.15	-0.80	0.20
V <sub>CCO</sub> + 0.85	1.02	-0.85	0.09
V <sub>CCO</sub> + 0.90	0.49	-0.90	0.04
V <sub>CCO</sub> + 0.95	0.24	-0.95	0.02

**Notes:**

1. A total of 200 mA per bank should not be exceeded.

**Table 5: Typical Quiescent Supply Current**

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
I <sub>CCINTQ</sub>	Quiescent V <sub>CCINT</sub> supply current	XC7A100T	155	155	155	108	mA	
		XC7A200T	328	328	328	232	mA	
I <sub>CCOQ</sub>	Quiescent V <sub>CCO</sub> supply current	XC7A100T	4	4	4	4	mA	
		XC7A200T	5	5	5	5	mA	
I <sub>CCAUXQ</sub>	Quiescent V <sub>CCAUX</sub> supply current	XC7A100T	36	36	36	36	mA	
		XC7A200T	73	73	73	73	mA	
I <sub>CCBRAMQ</sub>	Quiescent V <sub>CCBRAM</sub> supply current	XC7A100T	4	4	4	4	mA	
		XC7A200T	11	11	11	11	mA	

**Notes:**

1. Typical values are specified at nominal voltage, 85°C junction temperature (T<sub>j</sub>) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

**Table 6** shows the minimum current, in addition to  $I_{CCQ}$ , that is required by Artix-7 devices for proper power-on and configuration. If the current minimums shown in **Table 5** and **Table 6** are met, the device powers on after all four supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after  $V_{CCINT}$  is applied.

Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

**Table 6: Power-On Current for Artix-7 Devices<sup>(1)</sup>**

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	$I_{CCOMIN}$	$I_{CCBRAMMIN}$	Units
	Typ <sup>(2)</sup>	Typ <sup>(2)</sup>	Typ <sup>(2)</sup>	Typ <sup>(2)</sup>	
XC7A100T	$I_{CCINTQ} + 170$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7A200T	$I_{CCINTQ} + 340$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 80$	mA

**Notes:**

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.
2. Typical values are specified at nominal voltage, 25°C.

**Table 7: Power Supply Ramp Time**

Symbol	Description	Conditions	Min	Max	Units
$T_{VCCINT}$	Ramp time from GND to 90% of $V_{CCINT}$		0.2	50	ms
$T_{VCCO}$	Ramp time from GND to 90% of $V_{CCO}$		0.2	50	ms
$T_{VCCAUX}$	Ramp time from GND to 90% of $V_{CCAUX}$		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of $V_{CCBRAM}$		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	$T_J = 100^{\circ}\text{C}^{(1)}$	—	500	ms
		$T_J = 85^{\circ}\text{C}^{(1)}$	—	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms

**Notes:**

1. Based on 240,000 power cycles with nominal  $V_{CCO}$  of 3.3V or 36,500 power cycles with worst case  $V_{CCO}$  of 3.465V.

## DC Input and Output Levels

Values for  $V_{IL}$  and  $V_{IH}$  are recommended input voltages. Values for  $I_{OL}$  and  $I_{OH}$  are guaranteed over the recommended operating conditions at the  $V_{OL}$  and  $V_{OH}$  test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum  $V_{CCO}$  with the respective  $V_{OL}$  and  $V_{OH}$  voltage levels shown. Other standards are sample tested.

Table 8: SelectIO DC Input and Output Levels<sup>(1)(2)</sup>

I/O Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$	$V_{OH}$	$I_{OL}$	$I_{OH}$
	$V$ , Min	$V$ , Max	$V$ , Min	$V$ , Max	$V$ , Max	$V$ , Min	mA, Max	mA, Min
HSTL_I	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8.00	-8.00
HSTL_I_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8.00	-8.00
HSTL_II	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16.00	-16.00
HSTL_II_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16.00	-16.00
HSUL_12	-0.300	$V_{REF} - 0.130$	$V_{REF} + 0.130$	$V_{CCO} + 0.300$	20% $V_{CCO}$	80% $V_{CCO}$	0.10	-0.10
LVCMOS12	-0.300	35% $V_{CCO}$	65% $V_{CCO}$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 3	Note 3
LVCMOS15	-0.300	35% $V_{CCO}$	65% $V_{CCO}$	$V_{CCO} + 0.300$	25% $V_{CCO}$	75% $V_{CCO}$	Note 4	Note 4
LVCMOS18	-0.300	35% $V_{CCO}$	65% $V_{CCO}$	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	Note 5	Note 5
LVCMOS25	-0.300	0.7	1.700	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LVCMOS33	-0.300	0.8	2.000	3.450	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LVTTL	-0.300	0.8	2.000	3.450	0.400	2.400	Note 5	Note 5
MOBILE_DDR	-0.300	20% $V_{CCO}$	80% $V_{CCO}$	$V_{CCO} + 0.300$	10% $V_{CCO}$	90% $V_{CCO}$	0.10	-0.10
PCI33_3	-0.500	30% $V_{CCO}$	50% $V_{CCO}$	$V_{CCO} + 0.500$	10% $V_{CCO}$	90% $V_{CCO}$	1.50	-0.50
SSTL135	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	13.00	-13.00
SSTL135_R	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	8.90	-8.90
SSTL15	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	13.00	-13.00
SSTL15_R	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	8.90	-8.90
SSTL18_I	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.470$	$V_{CCO}/2 + 0.470$	8.00	-8.00
SSTL18_II	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.600$	$V_{CCO}/2 + 0.600$	13.40	-13.40

**Notes:**

- Tested according to relevant specifications.
- 3.3V and 2.5V standards are only supported in 3.3V I/O banks.
- Supported drive strengths of 4, 8, or 12 mA in HR I/O banks.
- Supported drive strengths of 4, 8, 12, or 16 mA in HR I/O banks.
- Supported drive strengths of 4, 8, 12, 16, or 24 mA in HR I/O banks.
- For detailed interface specific DC voltage levels, see [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).

## Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 12](#) correlates the current status of each Artix-7 device on a per speed grade basis.

[Table 12: Artix-7 Device Speed Grade Designations](#)

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7A100T	-2L (0.9V)		-3, -2, -2L (1.0V), -1
XC7A200T	-2L (0.9V)		-3, -2, -2L (1.0V), -1

## Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

[Table 13](#) lists the production released Artix-7 device, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

[Table 13: Artix-7 Device Production Software and Speed Specification Release](#)

Device	Speed Grade			
	1.0V			0.9V
	-3	-2/-2L	-1	-2L
XC7A100T	ISE 14.4 and Vivado 2012.4 with the 14.4/2012.4 device pack v1.07			
XC7A200T	ISE 14.4 and Vivado 2012.4 with the 14.4/2012.4 device pack v1.07			

**Notes:**

- Blank entries indicate a device and/or speed grade in advance or preliminary status.

## Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Artix-7 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 9](#).

**Table 14: Networking Applications Interface Performances**

Description	Speed Grade				Units	
	1.0V		0.9V			
	-3	-2/-2L	-1	-2L		
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	680	680	600	600	Mb/s	
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	1250	1250	950	950	Mb/s	
SDR LVDS receiver (SFI-4.1) <sup>(1)</sup>	680	680	600	600	Mb/s	
DDR LVDS receiver (SPI-4.2) <sup>(1)</sup>	1250	1250	950	950	Mb/s	

**Notes:**

- LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

**Table 15: Maximum Physical Interface (PHY) Rate for Memory Interfaces<sup>(1)(2)</sup>**

Memory Standard	Speed Grade				Units	
	1.0V		0.9V			
	-3	-2/-2L	-1	-2L		
<b>4:1 Memory Controllers</b>						
DDR3	1066	800	800	800	Mb/s	
DDR3L	800	800	667	667	Mb/s	
DDR2	800	800	667	667	Mb/s	
LPDDR2	667	667	533	533	Mb/s	
<b>2:1 Memory Controllers</b>						
DDR3	800	700	620	620	Mb/s	
DDR3L	800	700	620	620	Mb/s	
DDR2	800	700	620	620	Mb/s	

**Notes:**

- $V_{REF}$  tracking is required. For more information, see [UG586, 7 Series FPGAs Memory Interface Solutions User Guide](#).
- When using the internal  $V_{REF}$  the maximum data rate is 800 Mb/s (400 MHz).

Table 16: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T <sub>IOPI</sub>				T <sub>IOOP</sub>				T <sub>IOTP</sub>				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
HSTL_II_F	0.65	0.73	0.80	0.85	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
HSTL_I_18_F	0.67	0.75	0.82	0.87	1.13	1.26	1.51	1.72	1.70	1.92	2.34	2.37	ns	
HSTL_II_18_F	0.66	0.75	0.81	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
DIFF_HSTL_I_F	0.68	0.76	0.83	0.85	1.18	1.30	1.56	1.77	1.75	1.96	2.39	2.42	ns	
DIFF_HSTL_II_F	0.68	0.76	0.83	0.85	1.21	1.33	1.59	1.77	1.78	1.99	2.42	2.42	ns	
DIFF_HSTL_I_18_F	0.71	0.79	0.86	0.87	1.21	1.33	1.59	1.77	1.78	1.99	2.42	2.42	ns	
DIFF_HSTL_II_18_F	0.70	0.78	0.85	0.87	1.21	1.33	1.59	1.77	1.78	1.99	2.42	2.42	ns	
LVCMOS33_S4	1.26	1.34	1.41	1.62	3.80	3.93	4.18	4.41	4.37	4.59	5.01	5.06	ns	
LVCMOS33_S8	1.26	1.34	1.41	1.62	3.52	3.65	3.90	4.13	4.09	4.31	4.73	4.78	ns	
LVCMOS33_S12	1.26	1.34	1.41	1.62	3.09	3.21	3.46	3.69	3.65	3.87	4.29	4.34	ns	
LVCMOS33_S16	1.26	1.34	1.41	1.62	3.40	3.52	3.77	4.00	3.97	4.18	4.60	4.65	ns	
LVCMOS33_F4	1.26	1.34	1.41	1.62	3.26	3.38	3.64	3.86	3.83	4.04	4.46	4.51	ns	
LVCMOS33_F8	1.26	1.34	1.41	1.62	2.74	2.87	3.12	3.35	3.31	3.52	3.95	4.00	ns	
LVCMOS33_F12	1.26	1.34	1.41	1.62	2.55	2.68	2.93	3.16	3.12	3.34	3.76	3.81	ns	
LVCMOS33_F16	1.26	1.34	1.41	1.62	2.55	2.68	2.93	3.16	3.12	3.34	3.76	3.81	ns	
LVCMOS25_S4	1.12	1.20	1.27	1.43	3.13	3.26	3.51	3.72	3.70	3.91	4.34	4.37	ns	
LVCMOS25_S8	1.12	1.20	1.27	1.43	2.88	3.01	3.26	3.49	3.45	3.67	4.09	4.14	ns	
LVCMOS25_S12	1.12	1.20	1.27	1.43	2.48	2.60	2.85	3.08	3.05	3.26	3.68	3.73	ns	
LVCMOS25_S16	1.12	1.20	1.27	1.43	2.82	2.94	3.20	3.43	3.39	3.60	4.03	4.08	ns	
LVCMOS25_F4	1.12	1.20	1.27	1.43	2.74	2.87	3.12	3.35	3.31	3.52	3.95	4.00	ns	
LVCMOS25_F8	1.12	1.20	1.27	1.43	2.18	2.30	2.56	2.79	2.75	2.96	3.39	3.44	ns	
LVCMOS25_F12	1.12	1.20	1.27	1.43	2.16	2.29	2.54	2.77	2.73	2.95	3.37	3.42	ns	
LVCMOS25_F16	1.12	1.20	1.27	1.43	2.01	2.13	2.39	2.61	2.58	2.79	3.21	3.26	ns	
LVCMOS18_S4	0.74	0.83	0.89	0.94	1.62	1.74	1.99	2.19	2.19	2.40	2.82	2.84	ns	
LVCMOS18_S8	0.74	0.83	0.89	0.94	2.18	2.30	2.56	2.79	2.75	2.96	3.39	3.44	ns	
LVCMOS18_S12	0.74	0.83	0.89	0.94	2.18	2.30	2.56	2.79	2.75	2.96	3.39	3.44	ns	
LVCMOS18_S16	0.74	0.83	0.89	0.94	1.52	1.65	1.90	2.13	2.09	2.31	2.73	2.78	ns	
LVCMOS18_S24	0.74	0.83	0.89	0.94	1.60	1.72	1.98	2.21	2.17	2.38	2.81	2.86	ns	
LVCMOS18_F4	0.74	0.83	0.89	0.94	1.45	1.57	1.82	2.05	2.01	2.23	2.65	2.70	ns	
LVCMOS18_F8	0.74	0.83	0.89	0.94	1.68	1.80	2.06	2.29	2.25	2.46	2.89	2.94	ns	
LVCMOS18_F12	0.74	0.83	0.89	0.94	1.68	1.80	2.06	2.29	2.25	2.46	2.89	2.94	ns	
LVCMOS18_F16	0.74	0.83	0.89	0.94	1.40	1.52	1.77	2.00	1.97	2.18	2.60	2.65	ns	
LVCMOS18_F24	0.74	0.83	0.89	0.94	1.34	1.46	1.71	1.94	1.90	2.12	2.54	2.59	ns	
LVCMOS15_S4	0.77	0.86	0.93	0.98	2.05	2.18	2.43	2.50	2.62	2.84	3.26	3.15	ns	
LVCMOS15_S8	0.77	0.86	0.93	0.98	2.09	2.21	2.46	2.69	2.65	2.87	3.29	3.34	ns	
LVCMOS15_S12	0.77	0.86	0.93	0.98	1.59	1.71	1.96	2.19	2.15	2.37	2.79	2.84	ns	
LVCMOS15_S16	0.77	0.86	0.93	0.98	1.59	1.71	1.96	2.19	2.15	2.37	2.79	2.84	ns	

Table 16: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T <sub>IOPI</sub>				T <sub>IOOP</sub>				T <sub>IOTP</sub>				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
LVCMOS15_F4	0.77	0.86	0.93	0.98	1.85	1.97	2.23	2.27	2.42	2.63	3.06	2.92	ns	
LVCMOS15_F8	0.77	0.86	0.93	0.98	1.60	1.72	1.98	2.21	2.17	2.38	2.81	2.86	ns	
LVCMOS15_F12	0.77	0.86	0.93	0.98	1.35	1.47	1.73	1.96	1.92	2.13	2.56	2.61	ns	
LVCMOS15_F16	0.77	0.86	0.93	0.98	1.34	1.46	1.71	1.94	1.90	2.12	2.54	2.59	ns	
LVCMOS12_S4	0.87	0.95	1.02	1.08	2.57	2.69	2.95	3.18	3.14	3.35	3.78	3.83	ns	
LVCMOS12_S8	0.87	0.95	1.02	1.08	2.09	2.21	2.46	2.69	2.65	2.87	3.29	3.34	ns	
LVCMOS12_S12	0.87	0.95	1.02	1.08	1.79	1.91	2.17	2.40	2.36	2.57	2.99	3.05	ns	
LVCMOS12_F4	0.87	0.95	1.02	1.08	1.98	2.10	2.35	2.58	2.54	2.76	3.18	3.23	ns	
LVCMOS12_F8	0.87	0.95	1.02	1.08	1.54	1.66	1.92	2.15	2.11	2.32	2.75	2.80	ns	
LVCMOS12_F12	0.87	0.95	1.02	1.08	1.38	1.51	1.76	1.97	1.95	2.16	2.59	2.62	ns	
SSTL135_S	0.67	0.75	0.82	0.87	1.35	1.47	1.73	1.93	1.92	2.13	2.56	2.58	ns	
SSTL15_S	0.60	0.68	0.75	0.80	1.30	1.43	1.68	1.88	1.87	2.09	2.51	2.53	ns	
SSTL18_I_S	0.67	0.75	0.82	0.87	1.67	1.79	2.04	2.24	2.23	2.45	2.87	2.89	ns	
SSTL18_II_S	0.67	0.75	0.82	0.87	1.31	1.43	1.68	1.91	1.87	2.09	2.51	2.56	ns	
DIFF_SSTL135_S	0.68	0.76	0.83	0.87	1.35	1.47	1.73	1.93	1.92	2.13	2.56	2.58	ns	
DIFF_SSTL15_S	0.68	0.76	0.83	0.87	1.30	1.43	1.68	1.88	1.87	2.09	2.51	2.53	ns	
DIFF_SSTL18_I_S	0.71	0.79	0.86	0.87	1.68	1.80	2.06	2.24	2.25	2.46	2.89	2.89	ns	
DIFF_SSTL18_II_S	0.71	0.79	0.86	0.87	1.38	1.51	1.76	1.94	1.95	2.17	2.59	2.59	ns	
SSTL135_F	0.67	0.75	0.82	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
SSTL15_F	0.60	0.68	0.75	0.80	1.07	1.19	1.45	1.68	1.64	1.85	2.28	2.33	ns	
SSTL18_I_F	0.67	0.75	0.82	0.87	1.12	1.24	1.49	1.72	1.69	1.90	2.32	2.37	ns	
SSTL18_II_F	0.67	0.75	0.82	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
DIFF_SSTL135_F	0.68	0.76	0.83	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
DIFF_SSTL15_F	0.68	0.76	0.83	0.87	1.07	1.19	1.45	1.68	1.64	1.85	2.28	2.33	ns	
DIFF_SSTL18_I_F	0.71	0.79	0.86	0.87	1.23	1.35	1.60	1.80	1.79	2.01	2.43	2.45	ns	
DIFF_SSTL18_II_F	0.71	0.79	0.86	0.87	1.21	1.33	1.59	1.79	1.78	1.99	2.42	2.44	ns	

Table 17 specifies the values of T<sub>IOTPHZ</sub> and T<sub>IOIBUFDISABLE</sub>. T<sub>IOTPHZ</sub> is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). T<sub>IOIBUFDISABLE</sub> is described as the IOB delay from IBUFDISABLE to O output. In HR I/O banks, the internal IN\_TERM termination turn-off time is always faster than T<sub>IOTPHZ</sub> when the INTERMDISABLE pin is used.

Table 17: IOB 3-state Output Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
T <sub>IOTPHZ</sub>	T input to pad high-impedance	2.06	2.19	2.37	2.19	ns	
T <sub>IOIBUFDISABLE</sub>	IBUF turn-on time from IBUFDISABLE to O output	2.11	2.30	2.60	2.30	ns	

## Output Serializer/Deserializer Switching Characteristics

Table 21: OSERDES Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>Setup/Hold</b>						
T <sub>OSDCK_D</sub> /T <sub>OSCKD_D</sub>	D input setup/hold with respect to CLKDIV	0.42/0.03	0.45/0.03	0.63/0.03	0.44/-0.25	ns
T <sub>OSDCK_T</sub> /T <sub>OSCKD_T</sub> <sup>(1)</sup>	T input setup/hold with respect to CLK	0.69/-0.13	0.73/-0.13	0.88/-0.13	0.60/-0.25	ns
T <sub>OSDCK_T2</sub> /T <sub>OSCKD_T2</sub> <sup>(1)</sup>	T input setup/hold with respect to CLKDIV	0.31/-0.13	0.34/-0.13	0.39/-0.13	0.46/-0.25	ns
T <sub>oscck_oce</sub> /T <sub>osckc_oce</sub>	OCE input setup/hold with respect to CLK	0.32/0.58	0.34/0.58	0.51/0.58	0.21/-0.15	ns
T <sub>oscck_s</sub>	SR (reset) input setup with respect to CLKDIV	0.47	0.52	0.85	0.70	ns
T <sub>oscck_tce</sub> /T <sub>osckc_tce</sub>	TCE input setup/hold with respect to CLK	0.32/0.01	0.34/0.01	0.51/0.01	0.22/-0.15	ns
<b>Sequential Delays</b>						
T <sub>osccko_oq</sub>	Clock to out from CLK to OQ	0.40	0.42	0.48	0.54	ns
T <sub>osccko_tq</sub>	Clock to out from CLK to TQ	0.47	0.49	0.56	0.63	ns
<b>Combinatorial</b>						
T <sub>osdo_ttq</sub>	T input to TQ Out	0.83	0.92	1.11	1.18	ns

**Notes:**

- T<sub>OSDCK\_T2</sub> and T<sub>OSCKD\_T2</sub> are reported as T<sub>OSDCK\_T</sub>/T<sub>OSCKD\_T</sub> in TRACE report.

Table 23: IO\_FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>IO_FIFO Clock to Out Delays</b>						
T <sub>OFFCKO_DO</sub>	RDCLK to Q outputs	0.55	0.60	0.68	0.81	ns
T <sub>CKO_FLAGS</sub>	Clock to IO_FIFO flags	0.55	0.61	0.77	0.55	ns
<b>Setup/Hold</b>						
T <sub>CCK_D/T<sub>CKC_D</sub></sub>	D inputs to WRCLK	0.47/0.02	0.51/0.02	0.58/0.02	0.76/-0.05	ns
T <sub>IFFCCK_WREN/T<sub>IFFCKC_WREN</sub></sub>	WREN to WRCLK	0.42/-0.01	0.47/-0.01	0.53/-0.01	0.70/-0.05	ns
T <sub>OFFCCK_RDEN/T<sub>OFFCKC_RDEN</sub></sub>	RDEN to RDCLK	0.53/0.02	0.58/0.02	0.66/0.02	0.79/-0.02	ns
<b>Minimum Pulse Width</b>						
T <sub>PWH_IO_FIFO</sub>	RESET, RDCLK, WRCLK	1.62	2.15	2.15	2.15	ns
T <sub>PWL_IO_FIFO</sub>	RESET, RDCLK, WRCLK	1.62	2.15	2.15	2.15	ns
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	RDCLK and WRCLK	266.67	200.00	200.00	200.00	MHz

## CLB Switching Characteristics

Table 24: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
<b>Combinatorial Delays</b>							
T <sub>ILO</sub>	An – Dn LUT address to A	0.10	0.11	0.13	0.15	ns, Max	
T <sub>ILO_2</sub>	An – Dn LUT address to AMUX/CMUX	0.27	0.30	0.36	0.41	ns, Max	
T <sub>ILO_3</sub>	An – Dn LUT address to BMUX_A	0.42	0.46	0.55	0.65	ns, Max	
T <sub>I TO</sub>	An – Dn inputs to A – D Q outputs	0.94	1.05	1.27	1.51	ns, Max	
T <sub>AXA</sub>	AX inputs to AMUX output	0.62	0.69	0.84	1.01	ns, Max	
T <sub>AXB</sub>	AX inputs to BMUX output	0.58	0.66	0.83	0.98	ns, Max	
T <sub>AXC</sub>	AX inputs to CMUX output	0.60	0.68	0.82	0.98	ns, Max	
T <sub>AXD</sub>	AX inputs to DMUX output	0.68	0.75	0.90	1.08	ns, Max	
T <sub>BXB</sub>	BX inputs to BMUX output	0.51	0.57	0.69	0.82	ns, Max	
T <sub>BXD</sub>	BX inputs to DMUX output	0.62	0.69	0.82	0.99	ns, Max	
T <sub>CXC</sub>	CX inputs to CMUX output	0.42	0.48	0.58	0.69	ns, Max	
T <sub>CXD</sub>	CX inputs to DMUX output	0.53	0.59	0.71	0.86	ns, Max	
T <sub>DXD</sub>	DX inputs to DMUX output	0.52	0.58	0.70	0.84	ns, Max	
<b>Sequential Delays</b>							
T <sub>CKO</sub>	Clock to AQ – DQ outputs	0.40	0.44	0.53	0.62	ns, Max	
T <sub>SHCKO</sub>	Clock to AMUX – DMUX outputs	0.47	0.53	0.66	0.73	ns, Max	
<b>Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK</b>							
T <sub>AS/T<sub>AH</sub></sub>	A <sub>N</sub> – D <sub>N</sub> input to CLK on A – D flip-flops	0.07/0.12	0.09/0.14	0.11/0.18	0.11/0.20	ns, Min	
T <sub>DICK/T<sub>CKDI</sub></sub>	A <sub>X</sub> – D <sub>X</sub> input to CLK on A – D flip-flops	0.06/0.19	0.07/0.21	0.09/0.26	0.09/0.31	ns, Min	
	A <sub>X</sub> – D <sub>X</sub> input through MUXs and/or carry logic to CLK on A – D flip-flops	0.59/0.08	0.66/0.09	0.81/0.11	0.97/0.12	ns, Min	
T <sub>CECK_CLB/</sub> T <sub>CKCE_CLB</sub>	CE input to CLK on A – D flip-flops	0.15/0.00	0.17/0.00	0.21/0.01	0.34/–0.01	ns, Min	
T <sub>SRCK/T<sub>CKSR</sub></sub>	SR input to CLK on A – D flip-flops	0.38/0.03	0.43/0.04	0.53/0.05	0.62/0.05	ns, Min	
<b>Set/Reset</b>							
T <sub>SRMIN</sub>	SR input minimum pulse width	0.52	0.78	1.04	0.95	ns, Min	
T <sub>RQ</sub>	Delay from SR input to AQ – DQ flip-flops	0.53	0.59	0.71	0.83	ns, Max	
T <sub>CEO</sub>	Delay from CE input to AQ – DQ flip-flops	0.52	0.58	0.70	0.83	ns, Max	
F <sub>TOG</sub>	Toggle frequency (for export control)	1412	1286	1098	1098	MHz	

## CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 25: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
<b>Sequential Delays</b>							
T <sub>SHCKO</sub>	Clock to A – B outputs	0.98	1.09	1.32	1.54	ns, Max	
T <sub>SHCKO_1</sub>	Clock to AMUX – BMUX outputs	1.37	1.53	1.86	2.18	ns, Max	
<b>Setup and Hold Times Before/After Clock CLK</b>							
T <sub>DS_LRAM</sub> /T <sub>DH_LRAM</sub>	A – D inputs to CLK	0.54/0.28	0.60/0.30	0.72/0.35	0.96/0.40	ns, Min	
T <sub>AS_LRAM</sub> /T <sub>AH_LRAM</sub>	Address An inputs to clock	0.27/0.55	0.30/0.60	0.37/0.70	0.43/0.71	ns, Min	
	Address An inputs through MUXs and/or carry logic to clock	0.69/0.18	0.77/0.21	0.94/0.26	1.11/0.29	ns, Min	
T <sub>WS_LRAM</sub> /T <sub>WH_LRAM</sub>	WE input to clock	0.38/0.10	0.43/0.12	0.53/0.17	0.62/0.13	ns, Min	
T <sub>CECK_LRAM</sub> / T <sub>CKCE_LRAM</sub>	CE input to CLK	0.39/0.10	0.44/0.11	0.53/0.17	0.63/0.12	ns, Min	
<b>Clock CLK</b>							
T <sub>MPW_LRAM</sub>	Minimum pulse width	1.05	1.13	1.25	0.82	ns, Min	
T <sub>MCP</sub>	Minimum clock period	2.10	2.26	2.50	1.64	ns, Min	

**Notes:**

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.
2. T<sub>SHCKO</sub> also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

## CLB Shift Register Switching Characteristics (SLICEM Only)

Table 26: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
<b>Sequential Delays</b>							
T <sub>REG</sub>	Clock to A – D outputs	1.19	1.33	1.61	1.89	ns, Max	
T <sub>REG_MUX</sub>	Clock to AMUX – DMUX output	1.58	1.77	2.15	2.53	ns, Max	
T <sub>REG_M31</sub>	Clock to DMUX output via M31 output	1.12	1.23	1.46	1.68	ns, Max	
<b>Setup and Hold Times Before/After Clock CLK</b>							
T <sub>WS_SHFREG</sub> / T <sub>WH_SHFREG</sub>	WE input	0.37/0.10	0.41/0.12	0.51/0.17	0.59/0.13	ns, Min	
T <sub>CECK_SHFREG</sub> / T <sub>CKCE_SHFREG</sub>	CE input to CLK	0.37/0.10	0.42/0.11	0.52/0.17	0.60/0.12	ns, Min	
T <sub>DS_SHFREG</sub> / T <sub>DH_SHFREG</sub>	A – D inputs to CLK	0.33/0.34	0.37/0.37	0.44/0.43	0.54/0.47	ns, Min	
<b>Clock CLK</b>							
T <sub>MPW_SHFREG</sub>	Minimum pulse width	0.77	0.86	0.98	1.04	ns, Min	

**Notes:**

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Table 34: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
MMCM_F_BANDWIDTH	Low MMCM bandwidth at typical <sup>(1)</sup>	1.00	1.00	1.00	1.00	MHz
	High MMCM bandwidth at typical <sup>(1)</sup>	4.00	4.00	4.00	4.00	MHz
MMCM_T_STATPHAOFFSET	Static phase offset of the MMCM outputs <sup>(2)</sup>	0.12	0.12	0.12	0.12	ns
MMCM_T_OUTJITTER	MMCM output jitter	Note 3				
MMCM_T_OUTDUTY	MMCM output clock duty-cycle precision <sup>(4)</sup>	0.20	0.20	0.20	0.25	ns
MMCM_T_LOCKMAX	MMCM maximum lock time	100.00	100.00	100.00	100.00	μs
MMCM_F_OUTMAX	MMCM maximum output frequency	800.00	800.00	800.00	800.00	MHz
MMCM_F_OUTMIN	MMCM minimum output frequency <sup>(5)(6)</sup>	4.69	4.69	4.69	4.69	MHz
MMCM_T_EXTFDVAR	External clock feedback variation	< 20% of clock input period or 1 ns Max				
MMCM_RST_MINPULSE	Minimum reset pulse width	5.00	5.00	5.00	5.00	ns
MMCM_F_PFDMAX	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	450.00	MHz
MMCM_F_PFDMIN	Minimum frequency at the phase frequency detector	10.00	10.00	10.00	10.00	MHz
MMCM_T_FBDelay	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle				
<b>MMCM Switching Characteristics Setup and Hold</b>						
T_MMCM_DCK_PSEN/ T_MMCM_CKD_PSEN	Setup and hold of phase-shift enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_DCK_PSINCDEC/ T_MMCM_CKD_PSINCDEC	Setup and hold of phase-shift increment/decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_CKO_PSDONE	Phase shift clock-to-out of PSDONE	0.59	0.68	0.81	0.78	ns
<b>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</b>						
T_MMCM_DCK_DADDR/ T_MMCM_CKD_DADDR	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_DCK_DI/ T_MMCM_CKD_DI	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_DCK_DEN/ T_MMCM_CKD_DEN	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T_MMCM_DCK_DWE/ T_MMCM_CKD_DWE	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_CKO_DRDY	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_DCK	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

**Notes:**

- The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
- The static offset is measured between any MMCM outputs with identical phase.
- Values for this parameter are available in the Clocking Wizard.  
See [http://www.xilinx.com/products/intellectual-property/clocking\\_wizard.htm](http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm).
- Includes global clock buffer.
- Calculated as  $F_{VCO}/128$  assuming output duty cycle is 50%.
- When CLKOUT4\_CASCADE = TRUE, MMCM\_F\_OUTMIN is 0.036 MHz.

## Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

**Table 36: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Near Clock Region)**

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.							
TICKOF	Clock-capable clock input and OUTFF <i>without</i> MMCM/PLL (near clock region)	XC7A100T	5.14	5.74	6.72	7.64	ns
		XC7A200T	5.47	6.11	7.16	8.10	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

**Table 37: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Far Clock Region)**

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.							
TICKOFFAR	Clock-capable clock input and OUTFF <i>without</i> MMCM/PLL (far clock region)	XC7A100T	5.38	6.01	7.02	7.96	ns
		XC7A200T	6.17	6.89	8.05	9.05	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

**Table 38: Clock-Capable Clock Input to Output Delay With MMCM**

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> MMCM.							
TICKOFMMCMCC	Clock-capable clock input and OUTFF <i>with</i> MMCM	XC7A100T	0.89	0.94	0.96	1.81	ns
		XC7A200T	0.90	0.97	1.01	1.86	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

## Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

**Table 41: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD\_DELAY on HR I/O Banks**

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. <sup>(1)</sup>								
$T_{PSFD}/T_{PHFD}$	Full delay (legacy delay or default delay) global clock input and IFF <sup>(2)</sup> without MMCM/PLL with ZHOLD_DELAY on HR I/O banks	XC7A100T	2.69/-0.46	2.89/-0.46	3.34/-0.46	5.66/-0.52	ns	
		XC7A200T	3.03/-0.50	3.27/-0.50	3.79/-0.50	6.66/-0.53	ns	

**Notes:**

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input flip-flop or latch
3. A zero "0" hold time listing indicates no hold time or a negative hold time.

**Table 42: Clock-Capable Clock Input Setup and Hold With MMCM**

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. <sup>(1)</sup>								
$T_{PSMMCMCC}/T_{PHMMCMCC}$	No delay clock-capable clock input and IFF <sup>(2)</sup> with MMCM	XC7A100T	2.44/-0.62	2.80/-0.62	3.36/-0.62	2.15/-0.49	ns	
		XC7A200T	2.57/-0.63	2.94/-0.63	3.52/-0.63	2.32/-0.53	ns	

**Notes:**

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input flip-flop or latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

**Table 43: Clock-Capable Clock Input Setup and Hold With PLL**

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard. <sup>(1)</sup>								
$T_{PSPLLCC}/T_{PHPLLCC}$	No delay clock-capable clock input and IFF <sup>(2)</sup> with PLL	XC7A100T	2.78/-0.32	3.15/-0.32	3.78/-0.32	2.47/-0.60	ns	
		XC7A200T	2.91/-0.33	3.29/-0.33	3.94/-0.33	2.64/-0.63	ns	

**Notes:**

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input flip-flop or latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

## GTP Transceiver Specifications

### GTP Transceiver DC Input and Output Levels

Table 47 summarizes the DC output specifications of the GTP transceivers in Artix-7 FPGAs. Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further details.

Table 47: GTP Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
$DV_{PPOUT}$	Differential peak-to-peak output voltage <sup>(1)</sup>	Transmitter output swing is set to maximum setting	—	—	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
$R_{OUT}$	Differential output resistance		—	100	—	$\Omega$
$V_{CMOUTAC}$	Common mode output voltage: AC coupled		$1/2 V_{MGTAVTT}$			mV
$T_{OSKEW}$	Transmitter output pair (TXP and TXN) intra-pair skew (FFG, FBG, SBG packages)		—	—	10	ps
	Transmitter output pair (TXP and TXN) intra-pair skew (FGG, FTG, CSG packages)		—	—	12	ps
$DV_{PPIN}$	Differential peak-to-peak input voltage	External AC coupled	150	—	2000	mV
$V_{IN}$	Absolute input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	-200	—	$V_{MGTAVTT}$	mV
$V_{CMIN}$	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	—	$2/3 V_{MGTAVTT}$	—	mV
$R_{IN}$	Differential input resistance		—	100	—	$\Omega$
$C_{EXT}$	Recommended external AC coupling capacitor <sup>(2)</sup>		—	100	—	nF

#### Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

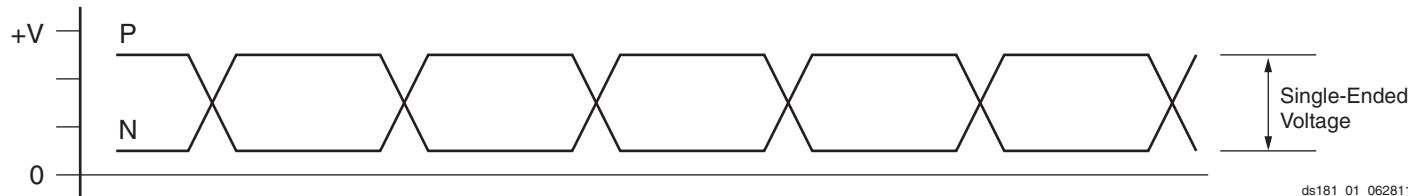


Figure 1: Single-Ended Peak-to-Peak Voltage

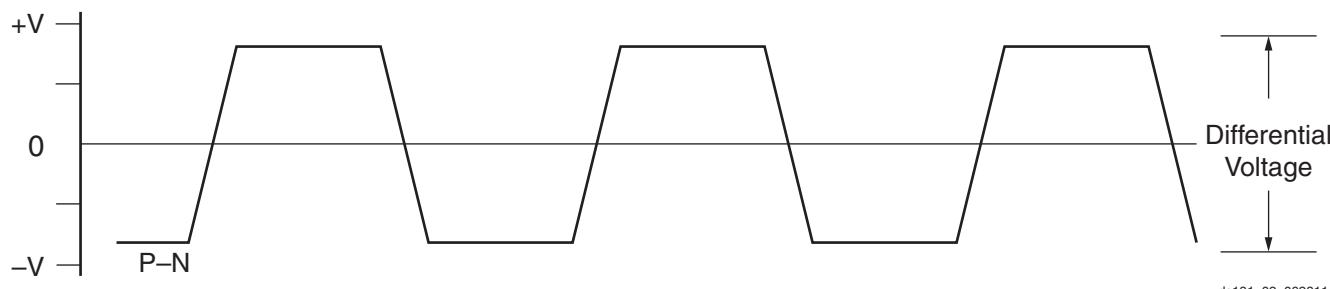


Figure 2: Differential Peak-to-Peak Voltage

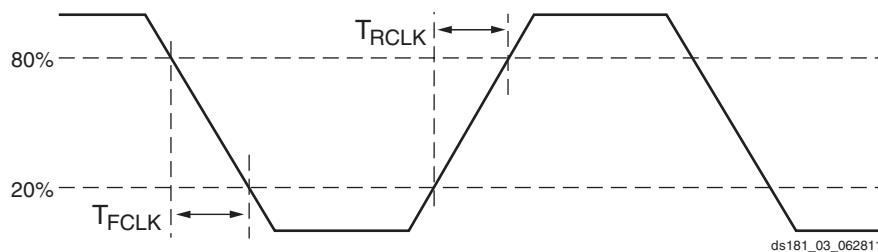


Figure 3: Reference Clock Timing Parameters

Table 52: GTP Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T <sub>LOCK</sub>	Initial PLL lock		—	—	1	ms
T <sub>DLOCK</sub>	Clock recovery phase acquisition and adaptation time.	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	2.3 x 10 <sup>6</sup>	UI

Table 53: GTP Transceiver User Clock Switching Characteristics<sup>(1)</sup>

Symbol	Description	Conditions	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
F <sub>TXOUT</sub>	TXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F <sub>RXOUT</sub>	RXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F <sub>TXIN</sub>	TXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F <sub>RXIN</sub>	RXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F <sub>TXIN2</sub>	TXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F <sub>RXIN2</sub>	RXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz

**Notes:**

1. Clocking must be implemented as described in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#).

## GTP Transceiver Protocol Jitter Characteristics

For Table 56 through Table 60, the [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

**Table 56: Gigabit Ethernet Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
<b>Gigabit Ethernet Transmitter Jitter Generation</b>				
Total transmitter jitter (T_TJ)	1250	–	0.24	UI
<b>Gigabit Ethernet Receiver High Frequency Jitter Tolerance</b>				
Total receiver jitter tolerance	1250	0.749	–	UI

**Table 57: XAUI Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
<b>XAUI Transmitter Jitter Generation</b>				
Total transmitter jitter (T_TJ)	3125	–	0.35	UI
<b>XAUI Receiver High Frequency Jitter Tolerance</b>				
Total receiver jitter tolerance	3125	0.65	–	UI

**Table 58: PCI Express Protocol Characteristics<sup>(1)</sup>**

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>PCI Express Transmitter Jitter Generation</b>					
PCI Express Gen 1	Total transmitter jitter	2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter	5000	–	0.25	UI
<b>PCI Express Receiver High Frequency Jitter Tolerance</b>					
PCI Express Gen 1	Total receiver jitter tolerance	2500	0.65	–	UI
PCI Express Gen 2 <sup>(2)</sup>	Receiver inherent timing error	5000	0.40	–	UI
	Receiver inherent deterministic timing error		0.30	–	UI

**Notes:**

1. Tested per card electromechanical (CEM) methodology.
2. Using common REFCLK.

**Table 59: CEI-6G Protocol Characteristics**

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
<b>CEI-6G Transmitter Jitter Generation</b>					
Total transmitter jitter <sup>(1)</sup>	4976–6375	CEI-6G-SR	–	0.3	UI
<b>CEI-6G Receiver High Frequency Jitter Tolerance</b>					
Total receiver jitter tolerance <sup>(1)</sup>	4976–6375	CEI-6G-SR	0.6	–	UI

**Notes:**

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.

**Table 60: CPRI Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
<b>CPRI Transmitter Jitter Generation</b>				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
<b>CPRI Receiver Frequency Jitter Tolerance</b>				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2 <sup>(1)</sup>	0.60	–	UI
	6144.0 <sup>(1)</sup>	0.60	–	UI

**Notes:**

1. Tested to CEI-6G-SR.

**Integrated Interface Block for PCI Express Designs Switching Characteristics**

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

**Table 61: Maximum Performance for PCI Express Designs**

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
FPIPECLK	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
FUSERCLK	User clock maximum frequency	250.00	250.00	250.00	250.00	MHz
FUSERCLK2	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
FRPCLK	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz

Table 63: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>Internal Configuration Access Port</b>						
F <sub>ICAPCK</sub>	Internal configuration access port (ICAPE2) clock frequency	100.00	100.00	100.00	70.00	MHz, Max
<b>Master/Slave Serial Mode Programming Switching</b>						
T <sub>DCCCK/T<sub>CCKD</sub></sub>	DIN setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T <sub>CCO</sub>	DOUT clock to out	8.00	8.00	8.00	9.00	ns, Max
<b>SelectMAP Mode Programming Switching</b>						
T <sub>SMDCCK/T<sub>SMCKD</sub></sub>	D[31:00] setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
T <sub>SMCSCK/T<sub>SMCKCS</sub></sub>	CSI_B setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T <sub>SMWCCK/T<sub>SMCKW</sub></sub>	RDWR_B setup/hold	10.00/0.00	10.00/0.00	10.00/0.00	12.00/0.00	ns, Min
T <sub>SMCKCSO</sub>	CSO_B clock to out (330 Ω pull-up resistor required)	7.00	7.00	7.00	8.00	ns, Max
T <sub>SMCO</sub>	D[31:00] clock to out in readback	8.00	8.00	8.00	10.00	ns, Max
F <sub>RBCCK</sub>	Readback frequency	100.00	100.00	100.00	70.00	MHz, Max
<b>Boundary-Scan Port Timing Specifications</b>						
T <sub>TAPTCK/T<sub>TCKTAP</sub></sub>	TMS and TDI setup/hold	3.00/2.00	3.00/2.00	3.00/2.00	3.00/2.00	ns, Min
T <sub>TCKTDO</sub>	TCK falling edge to TDO output	7.00	7.00	7.00	8.50	ns, Max
F <sub>TCK</sub>	TCK frequency	66.00	66.00	66.00	50.00	MHz, Max
<b>BPI Flash Master Mode Programming Switching</b>						
T <sub>BPICCO<sup>(2)</sup></sub>	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out	8.50	8.50	8.50	10.00	ns, Max
T <sub>BPIDCC/T<sub>BPICCD</sub></sub>	D[15:00] setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
<b>SPI Flash Master Mode Programming Switching</b>						
T <sub>SPIDCC/T<sub>SPICCD</sub></sub>	D[03:00] setup/hold	3.00/0.00	3.00/0.00	3.00/0.00	3.00/0.00	ns, Min
T <sub>SPICCM</sub>	MOSI clock to out	8.00	8.00	8.00	9.00	ns, Max
T <sub>SPICCFC</sub>	FCS_B clock to out	8.00	8.00	8.00	9.00	ns, Max

**Notes:**

1. To support longer delays in configuration, use the design solutions described in [UG470: 7 Series FPGA Configuration User Guide](#).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.

## eFUSE Programming Conditions

Table 64 lists the programming conditions specifically for eFUSE. For more information, see [UG470: 7 Series FPGA Configuration User Guide](#).

Table 64: eFUSE Programming Conditions<sup>(1)</sup>

Symbol	Description	Min	Typ	Max	Units
I <sub>FS</sub>	V <sub>CCAUX</sub> supply current	–	–	115	mA
t <sub>j</sub>	Temperature range	15	–	125	°C

**Notes:**

1. The FPGA must not be configured during eFUSE programming.